

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/709,784	CHAN ET AL.
Examiner	Art Unit	
Don P. Le	2819	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
326	27, 83	5/12/2005	DL
326	103	5/12/2005	DL